



FINAL PRODUCT/PROCESS CHANGE NOTIFICATION #20343CContinental Copy

Issue Date: 28-Oct-2014

TITLE: Release of an additional tester platform (T2000) for the **C383 / SCV78663** (currently tested on Micro Flex tester platform)

PROPOSED FIRST SHIP DATE: November 2014 after FPCN approval of Conti. First date code/delivery tested on T2000 will be provided to Conti.

AFFECTED CHANGE CATEGORY(S): Final test and QC insertions

FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:

Contact your local ON Semiconductor Sales Office, your customer quality interface (Veronique.Hooft@onsemi.com) or Xavier Van Esch (Xavier.VanEsch@onsemi.com)

NOTIFICATION TYPE:

Final Product/Process Change Notification (FPCN)

Final change notification sent to customers. FPCNs are issued at least 90 days prior to implementation of the change.

ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, your local ON Semiconductor Sales Office, your customer quality interface (Veronique.Hooft@onsemi.com) or Xavier Van Esch (Xavier.VanEsch@onsemi.com)

DESCRIPTION AND PURPOSE:

Release of T2000 tester platform for Final Test and QC to improve tester capacity balancing and loading.

Qualification data:

QC ambient correlation data between the source tester (Micro Flex) and the target tester (T2000) will be provided in a separate qualification report together with the Final PCN.

The correlation procedure will be used, like done as in previous PCN's covering the release of additional tester platforms

- 2 correlation units will be serialized and datalogged in 30 loops using the source tester platform where the device is already qualified. The test will be done at room temperature, using the QC program.
 - o Then, the same correlation units will be used to gather data on target tester T2000.
 - o The same datalogging procedure used for Micro Flex will be followed for T2000.



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Full parametric correlation will be performed and for every test the shift will be evaluated as follows:

$$\begin{aligned} \square \text{mean} &= \text{abs}(\text{mean}(\text{ref}) - \text{mean}(\text{qual})) \\ \square \text{sigma} &= 0 && \text{if } \text{sigma}(\text{qual}) < \text{sigma}(\text{ref}) \\ \square \text{sigma} &= \text{sigma}(\text{qual}) - \text{sigma}(\text{ref}) && \text{if } \text{sigma}(\text{qual}) > \text{sigma}(\text{ref}) \end{aligned}$$

$$\text{shift} = \square \text{mean} + 4 * \square \text{sigma}$$

If shift < max(5% specwidth, 6*sigma(ref)) then correlation is OK for this test,
else correlation is NOK for this test

Any parameter that is NOK is independently analyzed and explained.

- 10 Rejects from Hot and 10 rejects from Cold will be serialized and datalogged on Micro Flex. The same devices will be tested on T2000. Results should match, deviations must be explained.

The correlation data can be found in report "C383_uflex to T2000_Device_Test_Qualification_Report"

ELECTRICAL CHARACTERISTIC SUMMARY:

Electrical Performance will continue to meet specifications.

List of affected Customer Specific Parts:

Conti part number	ON Semi part number
A2C00062880	SCV78663DQ1R2G (0C383-002-XTP)